

In-situ test of pultruded parts with the Non-Ionizing Direct Imaging Testing method NIDIT

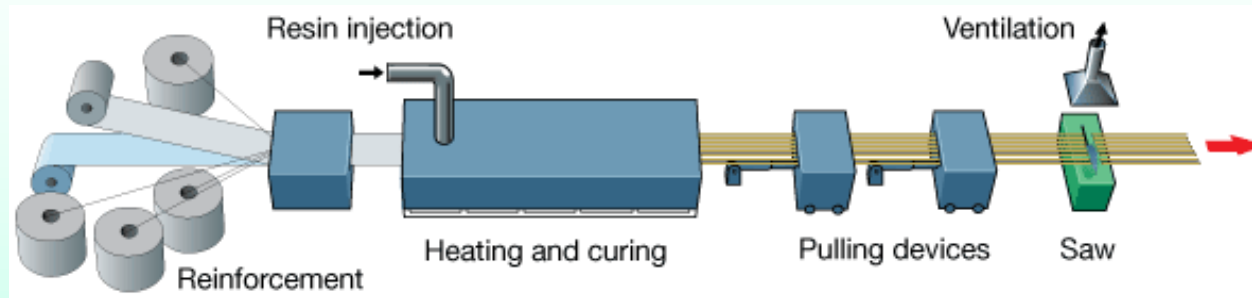
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1. Introduction
2. Principles of the non-destructive test method NIDIT
3. Examples
4. Conclusions

Pultrusion with control loop

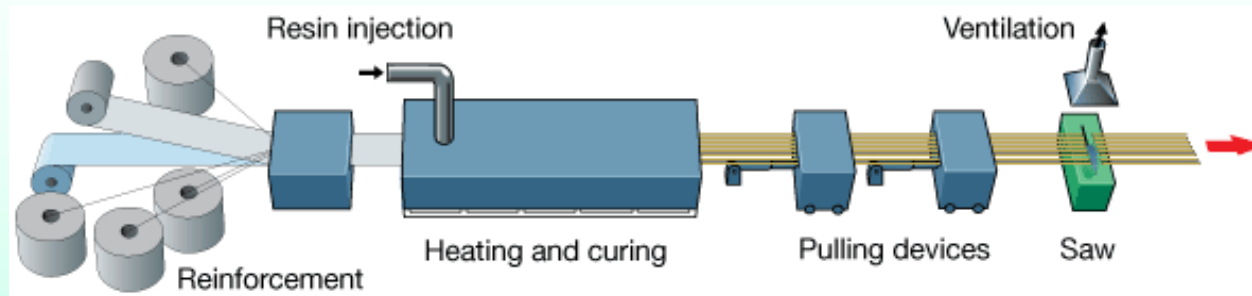
Basic principle of pultrusion plant, <https://fiberline.com/pultrusion>



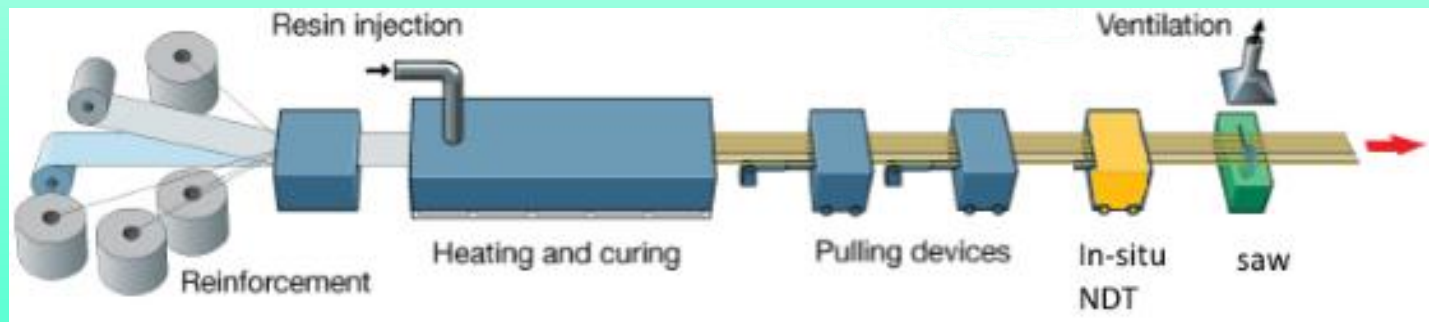
- Process parameters: temperature of resin, temperature of die, pulling speed, ...
- Desirable: adjust process parameters quickly in a closed control loop
- >> In-situ non-destructive testing (NDT) in the control loop

Control loop with in-situ NDT

Basic principle of pultrusion plant, <https://fiberline.com/pultrusion>

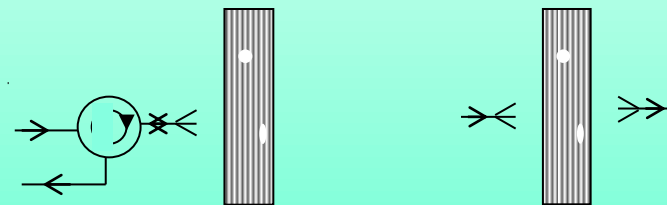


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Basics of microwave testing (μT)

- microwaves: electromagnetic waves in the frequency region 300 MHz ... 300 GHz
- microwave testing makes use of local variations of dielectric constant ϵ_R of the transparent material
- ---> refraction, diffraction and reflection as in optics.
- dielectric constants ϵ_R : E-Glas 5.8 ... 6.7; epoxy 2 ... 3; air 1.0



Two principles are possible: reflection and transmission

- >> basically local methods
- may be time-consuming when scanning over certain areas
- direct imaging procedure is desirable

Basics of NIDIT

X-ray radiography:

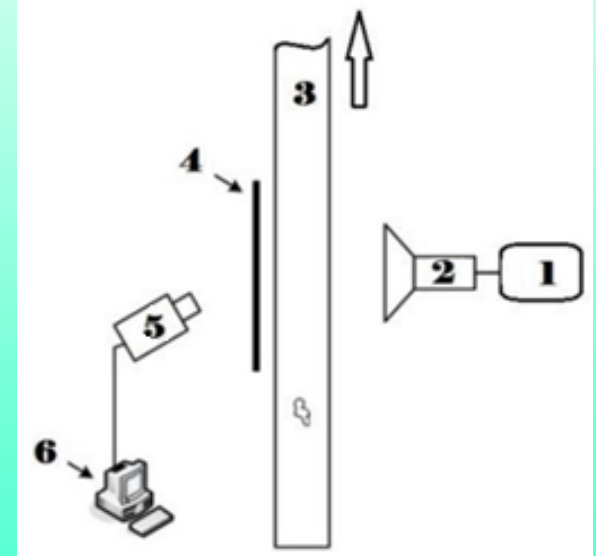
- powerful, direct imaging method of NDT
- high spatial resolution
- however: X-rays are ionizing and therefore harmful >> high safety measures necessary >> limits industrial use

NIDIT:

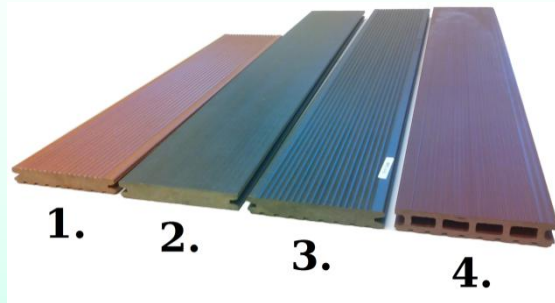
- If the devices under test (DUTs) are electrically insulating and
- high spatial resolution of X-rays are not absolutely necessary
- **>> direct imaging with microwaves (NIDIT – Non-Ionizing Direct Imaging Testing)**
- microwaves are non-ionizing and therefore harmless

The basic NIDIT setup

- (1) microwave source
- (2) antenna: irradiates widespread the
- (3) device under test (DUT). The homogeneously incident microwave radiation is affected by inhomogeneities, i.e. defects, and such inhomogeneously leaks the DUT. It hits the
- (4) microwave absorbing foil which accordingly is heated inhomogeneously. This heat distribution is recorded by an
- (5) infrared camera and forwarded to a
- (6) computer where it is instantly displayed and represents the defect distribution. Foil and camera act as a microwave detector.



NIDIT test of extruded WPC planks WPC – wood plastic composite



Tested WPC planks. From left:

1. profiled with crack
2. plane with crack
3. profiled without defects
4. hollow chamber profile with defects, from construction market

Snapshots of 4 videos of
through passing WPC
planks

plank 1:
profiled with crack,
in the crack region



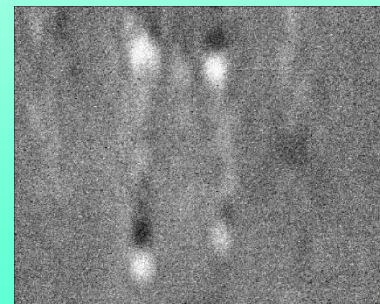
plank 2:
plane with crack,
in the crack region



plank 3:
profiled without defects,
typical image

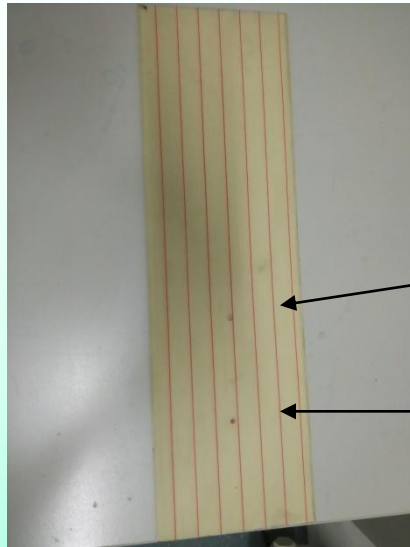


plank 4:
hollow chamber profile with
defects. Off-the-shelf from
construction market. Typical
image.



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NIDIT test of pultruded GFRP plank GFRP – glass fibre reinforced plastic

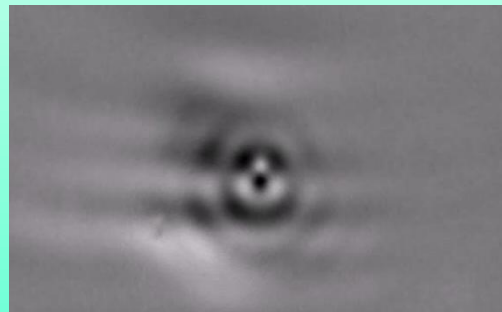


Length (mm)	450
Width (mm)	150
Depth (mm)	2.5

Defect 1:
1 mm diameter artificially drilled
hole, 1 mm deep

Defect 2:
1 mm diameter artificially drilled
through hole, 2.5 mm deep

Snapshots of video of
through passing GFRP
plank with artificial defects



Snapshot of video sequence of
induced defect 1



Snapshot of video sequence of
induced defect 2

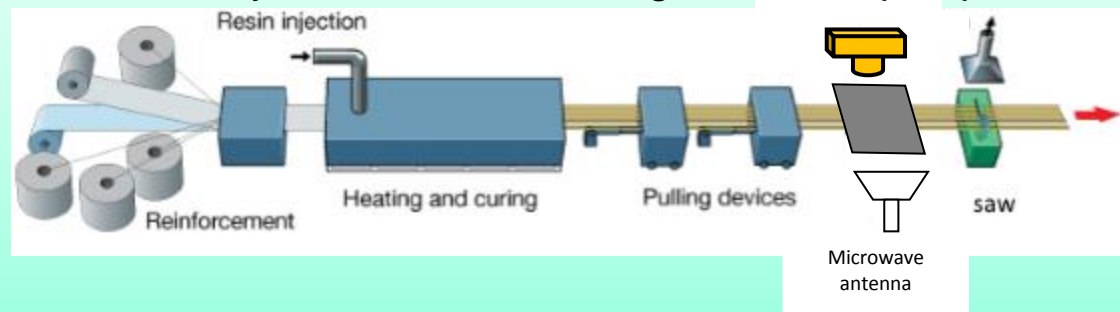
Conclusion

Remarks:

- Sliding difference evaluation for improved defect recognition. Especially suited for 2D-structures, i.e. in pultrusion processes.
- GFRP plate: contacting absorbing foil with sacrificial PE foil in between

Suggestion:

- In-line NIDIT NDT system for fast reacting control loop in pultrusion process



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